

MOSFET – P-Channel, QFET

-60 V, -30 A, 26 m Ω

FQPF47P06, FQPF47P06YDTU

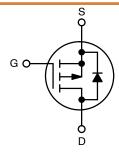
Description

This P-Channel enhancement mode power MOSFET is produced using **onsemi**'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- -30 A, -60 V, $R_{DS(on)} = 26 \text{ m}\Omega$ (Max.) @ $V_{GS} = -10 \text{ V}$, $I_D = -15 \text{ A}$
- Low Gate Charge (Typ. 84 nC)
- Low Crss (Typ. 320 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating

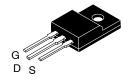
V _{DSS}	R _{DS(ON)} MAX	I _D MAX	
-60 V	26 mΩ @ -10 V	–30 A	



P-Channel MOSFET

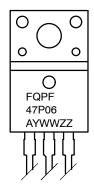


TO-220 Fullpack, 3-Lead / TO-220F-3SG CASE 221AT



TO-220-3LD LF CASE 340BJ

MARKING DIAGRAM



FQPF47P06 = Specific Device Code
A = Assembly Location
YWW = Date Code (Year & Week)
ZZ = Assembly Lot

ORDERING INFORMATION

Device	Package	Shipping
FQPF47P06	TO-220-3 Fullpack (Pb-Free)	1000 Units / Tube
FQPF47P06YDTU	TO-220-3 (Pb-Free)	800 Units / Tube

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise specified)

Symbol	Parameter		FQPF47P06 / FQPF47P06YDTU	Unit
V _{DSS}	Drain-Source Voltage		-60	V
I _D	Drain Current	– Continuous (T _C = 25°C)	-30	Α
		- Continuous (T _C = 100°C)	-21.2	Α
I _{DM}	Drain Current (Note 1)	- Pulsed	-120	Α
V_{GSS}	Gate-Source Voltage		+ 25	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		820	mJ
I _{AR}	Avalanche Current (Note 1)		-30	Α
E _{AR}	Repetitive Avalanche Energy (Note	: 1)	6.2	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3	3)	-7.0	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		62	W
		- Derate above 25°C	0.41	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		−55 to +175	°C
T_L	Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 5 Seconds		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. L = 1.06 mH, $I_{AS} = -30$ A, $V_{DD} = -25$ V, $R_G = 25$ Ω , Starting $T_J = 25^{\circ}C$
3. $I_{SD} \le -47$ A, di/dt ≤ 300 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

THERMAL CHARACTERISTICS

Symbol	Characteristic		Max	Unit
$R_{ hetaJC}$	Thermal Resistance, Junction-to-Case		2.42	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient	-	62.5	°C/W

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHAR	ACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	-60		_	V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C	-	-0.06	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	-1	μΑ
		V _{DS} = -48 V, T _C = 150°C	-	-	-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 25 V, V _{DS} = 0 V	-	-	100	nA
ON CHAR	ACTERISTICS					
V _{GS(th})	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0	-	-4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, I_D = -15 \text{ A}$	-	0.021	0.026	Ω
9FS	Forward Transconductance	$V_{DS} = -30 \text{ V}, I_D = -15 \text{ A (Note 4)}$	-	19	-	S
DYNAMIC	CHARACTERISTICS					
C _{iss}	Input Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$	-	2800	3600	pF
C _{oss}	Output Capacitance	7	-	1300	1700	pF
C _{rss}	Reverse Transfer Capacitance	7	-	320	420	pF
SWITCHIN	G CHARACTERISTICS	•				
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -30 \text{ V}, I_D = -23.5 \text{ A}, R_G = 25 \Omega$	-	50	110	ns
t _r	Turn-On Rise Time	(Note 4, 5)	-	450	910	ns
t _{d(off)}	Turn-Off Delay Time	7	-	100	210	ns
t _f	Turn-Off Fall Time	7	-	195	400	ns
Qg	Total Gate Charge	$V_{DS} = -48 \text{ V}, I_D = -47 \text{ A}, V_{GS} = -10 \text{ V}$	-	84	110	nC
Q _{gs}	Gate-Source Charge	(Note 4, 5)	-	18	_	nC
Q _{gd}	Gate-Drain Charge	7	-	44	_	nC
DRAIN-SO	DURCE DIODE CHARACTERISTICS AND MAX	IMUM RATING				
IS	Maximum Continuous Drain-Source Diode Forward Current		-	-	-30	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		-	-	-120	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -30 \text{ A}$	_	-	-4.0	V
	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = -47 \text{ A},$	_	130	_	ns
t _{rr}	· · · · · · · · · · · · · · · · · · ·	$dl_{\rm F}/dt = 100 {\rm A/\mu s} ({\rm Note} 4)$				

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: Pulse width ≤ 300 µs, Duty cycle ≤ 2%

5. Essentially independent of operating temperature

TYPICAL CHARACTERISTICS

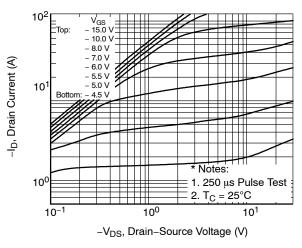


Figure 1. On-Region Characteristics

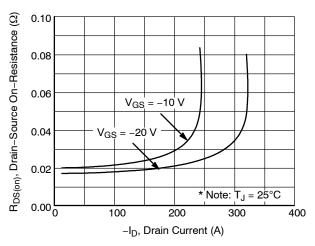


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

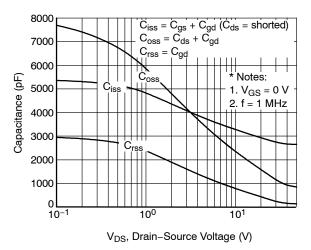


Figure 5. Capacitance Characteristics

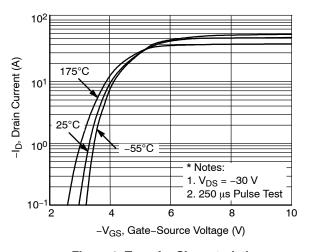


Figure 2. Transfer Characteristics

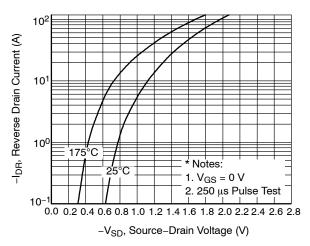


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

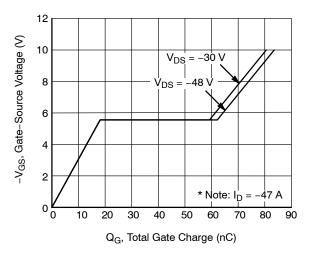


Figure 6. Gate Charge Characteristics

TYPICAL CHARACTERISTICS (CONTINUED)

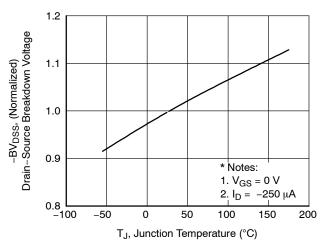


Figure 7. Breakdown Voltage Variation vs. Temperature

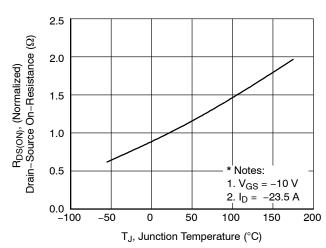


Figure 8. On–Resistance Variation vs. Temperature

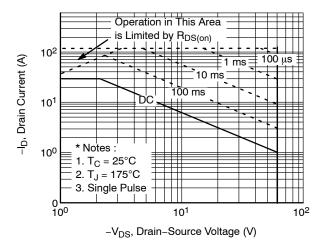


Figure 9. Maximum Safe Operating Area

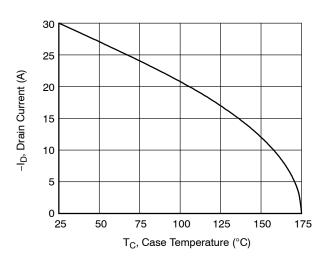


Figure 10. Maximum Drain Current vs. Case Temperature

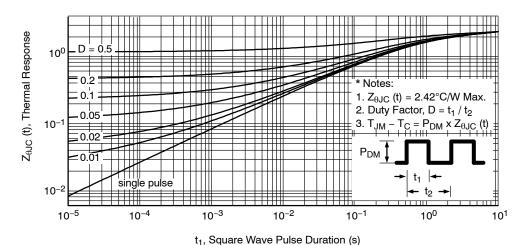


Figure 11. Transient Thermal Response Curve

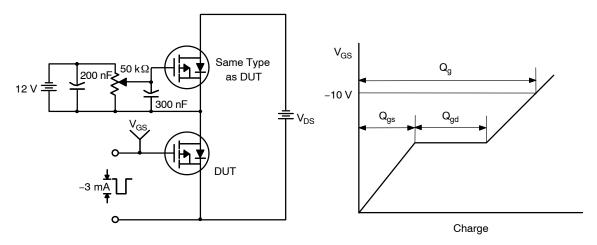


Figure 12. Gate Charge Test Circuit & Waveform

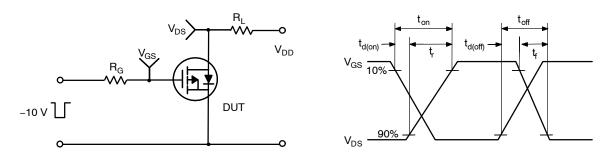


Figure 13. Resistive Switching Test Circuit & Waveforms

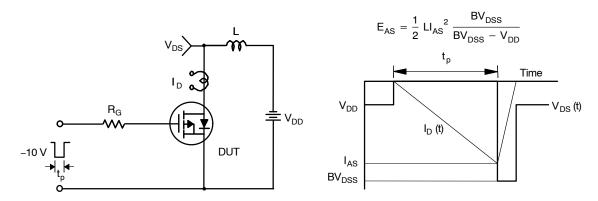
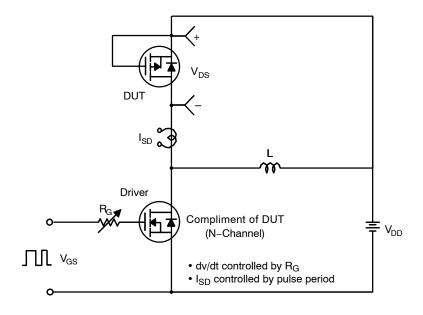


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



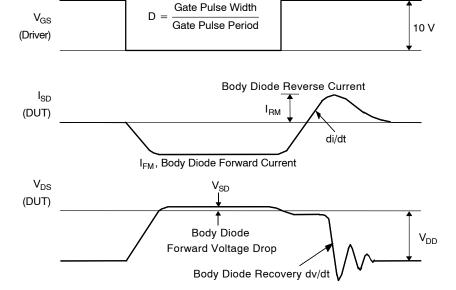
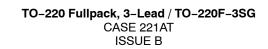
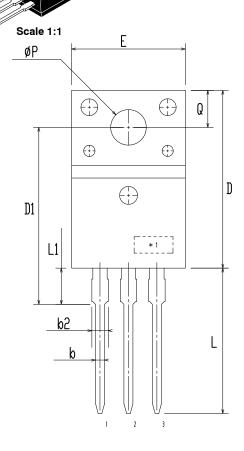
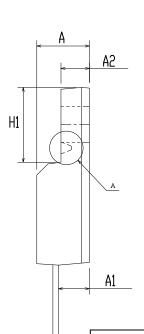


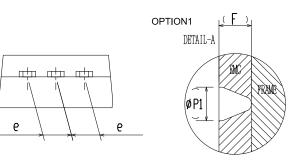
Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



DATE 19 JAN 2021







DIM	MILLIMITERS			
ויונע	MIN	NDM	MAX	
Α	4.50	4.70	4.90	
A1	2.56	2.76	2.96	
A2	2.34	2.54	2.74	
b	0.70	0.80	0.90	
b2	~	2	1.47	
С	0.45	0.50	0.60	
D	15.67	15.87	16.07	
D1	15.60	15.80	16.00	
E	9.96	10.16	10.36	
е	2.34	2.54	2.74	
F	~	0.84	2	
H1	6.48	6.68	6.88	
L	12.78	12.98	13.18	
L1	3.03	3.23	3.43	
ØΡ	2.98	3.18	3.38	
Ø P1	~	1.00	~	
Q	3.20	3.30	3.40	

MILLIMITEDS

NOTES:

- A. DIMENSION AND TOLERANCE AS ASME Y14.5-2009
- B. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUCSIONS.

C

C. OPTION 1 - WITH SUPPORT PIN HOLE OPTION 2 - NO SUPPORT PIN HOLE

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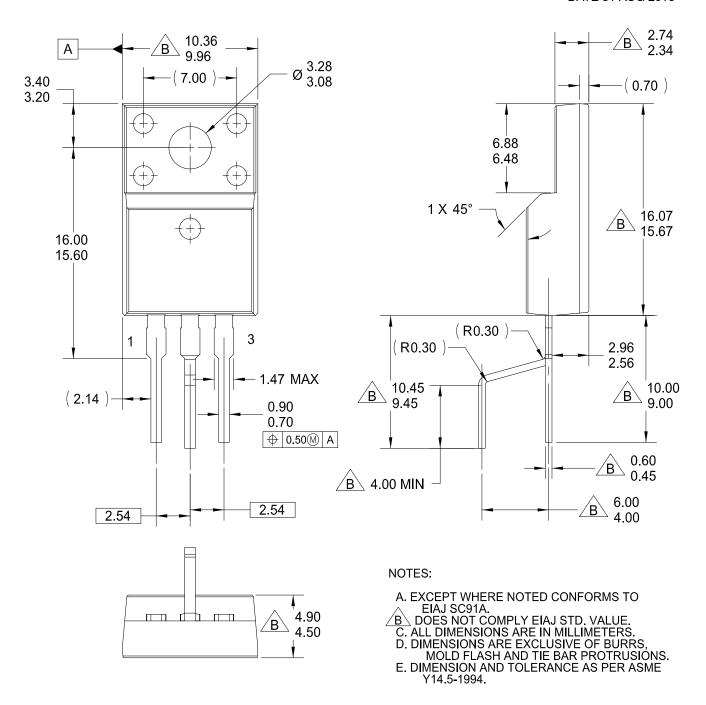
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TO-220-3LD LF CASE 340BJ ISSUE O

DATE 31 AUG 2016



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